

Usages of Memristors

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ABSTRACT

Recently, advances in traditional computer memory technologies have begun to decelerate as *CMOS*, complementary metal-oxide semiconductor, based computing is reaching physical barriers to scaling. This has resulted in less than spectacular improvements to performance, energy efficiency, and density. Some researchers and companies are starting to see alternative computing architectures as viable replacements to provide continued incremental improvements to computing performance. One such technology is the memristor developed by a research team headed by R. Stanley Williams in 2008. These memristors are being developed in order to implement the crossbar array that has the potential to replace standard transistor based CPU architectures and many different memory formats as the memristor has the potential to be a *universal memory* (a data storage device that is suitable for all types of memory storage). It meets the requirements of a universal memory as it theoretically has read/write times faster than DRAM, densities greater than DRAM, non-volatility, long life span, and it is also suitable for performing logic.

Keywords

memristor, crossbar array, computation-in-memory, 1T1R, non-volatile, memristive

1. INTRODUCTION

Various aspects of modern computing technologies have begun to reach their limits. Sustaining trends in processing speed, data storage, and energy efficiency in CMOS (complementary metal-oxide semiconductor) based computing is becoming more and more difficult as memories like DRAM (dynamic random access memory) and Flash begin to reach scaling limits. Increases in CPU and memory sizes have also begun to exasperate communication bottlenecks in current computing architectures. These issues have spurred research and development into alternate memory types. The one covered in this paper is the memristor, developed in 2008 by a

research team headed by R Stanley Williams [8]. This memory has the potential alleviate the aforementioned issues as it has properties that make it a possible universal memory, in that it is suitable for use in both main memory and data storage due to its impressive state change times and ability to retain its state for years without power. On top of this it has the potential to implement a computing architecture that can avoid time and energy inefficient communication bottlenecks.

Section 2 of this paper will first give background information on the memristor which will go over its properties as well as attempt to cover the history of the memristor. A short introduction to the crossbar array will also be provided in the background. In section 3 the memristor will be compared to other memories to show how it holds up as a memory. Section 4 shows how memristors operate as logic switches. Then section 5 one of the applications of the memristor that makes use of the crossbar array will be covered along with some results of simulations using the architecture compared to conventional computing. To deal with a certain issue facing crossbar arrays a simple memristor cell will be shown in section 6 along with read and write time/energy models of this cell. Another interesting application that has been receiving a lot of attention will also be briefly covered in Section 7.

2. BACKGROUND INFORMATION

2.1 The Memristor

The *memristor* is a *non-volatile* memory which retains information without power supply as a state of resistance depending on the history of applied current. The original memristor as depicted in Figure 1 was constructed by placing a layer of highly resistive Titanium Dioxide, TiO_2 , and a conductive layer of TiO_2 which has had some amount of oxygen atoms removed that is represented as TiO_{2-x} . These two layers are placed between two electrodes. These electrodes would most likely be made of platinum and would be part of the crossbar array which will be covered later. The state of the memristor is altered by passing a current through it. This is different from more conventional memories like the volatile DRAM which stores information within a capacitor. A capacitor with no charge would be read as a 0 and a capacitor that is fully charged would be a 1.

A more in-depth explanation of how the memristor works is as follows. When a positive voltage is passed through the electrode on the TiO_{2-x} side of the memristor it will cause vacancies to be pushed down into the TiO_2 . This results in the TiO_{2-x} increasing in thickness while the TiO_2

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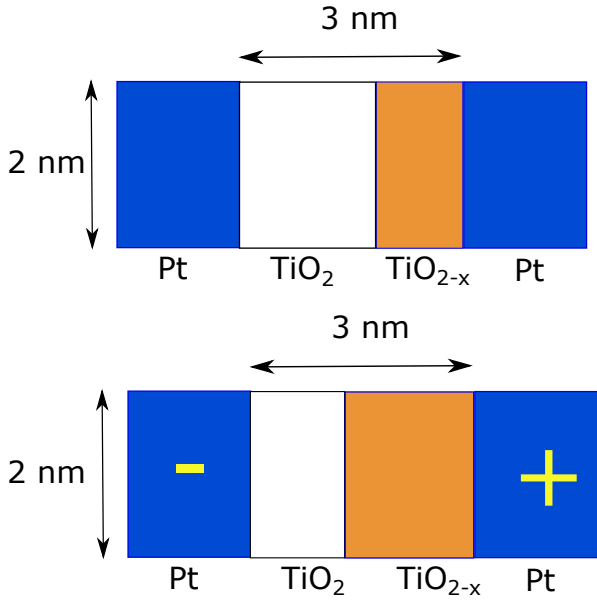


Figure 1: Simple depiction of a memristor. Pt is the platinum electrodes, nm for nano-meters. A resistive layer of TiO_2 and conductive layer of TiO_{2-x} with oxygen vacancies. The current applied to the memristor causes the oxygen vacancies to move, altering the ratio of conductive/resistive portions, leading to overall change of resistance.

shortens. This increase in width of the conductive region and decrease in width of the resistive region. It also significantly reduces the overall resistance as resistance of a material is determined by both its resistive properties and overall length. The overall width of a memristor can be constructed to be only a few nano meters or less, so it doesn't take much of a change in size of the resistive layer to have a large impact on the resistance. This results in the memristor having a R_{ON}/R_{OFF} ratio > 1000 , where R_{OFF} and R_{ON} are the resistances of the memristor that correspond to 0 or 1, respectively. This also happens fairly quickly, giving memristors switching times of nano seconds. In order to read the memristor without disturbing its state, it is simple enough to use alternating current since alternating the current will result in no movement of the oxygen vacancies.

The memristor was originally hypothesized as the fourth missing circuit element by Chua in 1971, with the others being the resistor, capacitor, and inductor [3]. The theoretical memristor specifies a linkage between magnetic flux and charge. It was not until recently in 2008 that claims of the physical realization of the memristor were made by R. Stanley Williams's research team at Hewlett Packard [8]. There has been debate over whether the 2008 memristor really is the theoretical memristor.

The 2008 "memristor" was not the first device created to exhibit memristive properties, however these devices were never claimed to be memristors. In fact, the memristive properties of TiO_2 were known as far back as 1966, but the research was not cited by William's et al. in 2008 [1] [8]. Leon Chua replied to these criticisms in 2011 by stating that all memristive memories can be classified as memristors

| | Memristor | PCM | STT-RAM | DRAM | Flash | HD |
|-----------------------------|-----------|---------------|-----------|-------------------|-----------------|-------------------|
| Chip area per bit (F^2) | 4 | 8-16 | 14-64 | 6-8 | 4-8 | |
| Energy per bit (μJ) | 0.1-3 | 2-100 | 0.1-1 | 2-4 | $10^1 - 10^3$ | $10^6 - 10^7$ |
| Read time (ns) | <10 | 20-70 | 10-30 | 10-50 | 25,000 | $5-8 \times 10^6$ |
| Write time (ns) | 20-30 | 50-500 | 13-95 | 10-50 | 200,000 | $5-8 \times 10^6$ |
| Retention | 10 years | <10 years | Weeks | $< \text{Second}$ | ~ 10 years | ~ 10 years |
| Endurance (cycles) | 10^{12} | $10^7 - 10^8$ | 10^{15} | 10^{17} | $10^3 - 10^6$ | 10^{15} |
| 3D capability | Yes | No | No | No | Yes | |

Table 1: [4] Comparison of different memories. From left to right: PCM is phase change memory, STT-RAM is MRAM (magnetic RAM), DRAM (dynamic RAM) is currently used for main memory, flash memory used in SSD's, and HD. At the moment everything other than DRAM, flash, and HD are under development

[2]. In 2015 Vongher claimed that the current "memristor" is more than likely another implementation of existing memristive memory types, as the conceptual memristor is not possible without magnetic induction [10].

The HP memristor appears to be another implementation of oxidation based RRAM (resistive RAM), which uses compounds with similar properties (capable of oxygen exchanges that result in resistance changes) to the memristor to store information as resistance. In fact, many research papers use the terms memristor and RRAM interchangeably and the HP memristor appears to specifically be redox-based RRAM. Redox-based resistive RAM is essentially what the described memristor is but without the memristor name. This should not affect the results of the research though, as it would appear that the physical properties of the "memristor" are true to the explanation given above, and that the criticism is that the "memristor" is not equivalent to the original theoretical memristor. For simplicity and to avoid confusion I will continue to refer to the HP device as a memristor as that is what the research I am covering calls it.

2.2 Crossbar Array

When reading research on memristors it is rare to not find mention of the crossbar array. The crossbar array is simply a collection of switches arranged in a matrix pattern. It was originally invented by HP in 2001. From then on HP researchers were searching for a switching material with a high enough Off/On ratio to work with it. Implementing a nano-scale crossbar array was the motivation behind the development of the memristor by R. Stanley Williams's team [8]. The interest in the crossbar array is due in part to its impressive scaling capabilities (down to 5 nm) and its simplicity allows it to be cheaply manufactured [5].

3. MEMRISTORS AS MEMORY

One of the most obvious uses of memristors is as a memory. Table 1 provides a chart of some of the advantages memristors have over other memory storage types [4]. In Table 1 the retention is how long after a write will a bit still have the original value, endurance is how many times a the memory can be written to before becoming unusable, and 3D capability refers to whether the memory arrays can be

stacked in a reasonable way. The source is from an article by HP, but comparing the results to similar RRAM tables these results seem to be accurate. They have significant advantages in density, read/write time, data retention, cycles (endurance), and energy consumption. Crossbar arrays allow them to be densely stacked into a three dimensional block with the potential to store petabytes of memory within a cubic centimeter. Not shown in the chart, memristors have also drawn particular interest as they can potentially be cheaply manufactured using techniques for manufacturing traditional CMOS technology. When looking at the table it would also appear that DRAM is only slightly less energy efficient than memristors but this is not true. What is shown is the power to access a bit of DRAM once, but it does not account for the fact that DRAM must continually be refreshed, causing it to consume large amount of power relative to the other memories in the table.

The last three columns are memories that most are familiar with. When referring to RAM for computers that is usually referring to DRAM, the main memory that the CPU accesses. DRAM has the highest endurance, roughly five orders of magnitude higher than memristors, so it may be possible that memristors would have some trouble being used as main memory due to endurance issues. Both Flash and HD are used for mass storage as their read and write times are too long and they are not bit accessible like RAM as memory is accessed in chunks rather than on a per bit basis.

The other two memories mentioned in the table are still in development. They have yet to hit the market in any meaningful way despite being in development for much longer than memristors. They both have some similarities to memristors as they are both non-volatile RAMs and are being developed as possible replacements to current memory types. STT-RAM or spin transfer torque RAM, is the newest implementation of magnetoresistive RAM. There is not a good way of explaining its mechanism in a way that makes sense but is also short so for further clarification the wikipedia article on it is a good place to look [12]. It has the lowest power consumption in the table as well as the second highest endurance and respectable read/write times, but it suffers from having a large feature size. Similar to the memristor, phase change memory stores a state as resistance, and it was even argued by Leon Chua that it should be classified as a type of memristor [2]. Its method of changing its resistance is significantly different though. The material used is Chalcogenide which is the same material used in CDs and DVDs. In this case its state is changed by melting it into either a conductive crystalline state or a resistive amorphous state. As seen in the table this memory to has drawbacks compared to memristors and even DRAM. Both PCM and STT-RAM will not likely be manufactureable using techniques used in manufacturing CMOS like the memristor [11] [12].

The memristor also has plenty of room for improvement. The original memristor was made using TiO_2 , however there have been memristors made using other materials with excellent properties. For example a more recent implementation using tantalum oxide has been shown to have switching times from 105 to 120 pico seconds, or one-hundredth of the write times shown in Table 1 [9].

4. MEMRISTORS AS LOGIC SWITCHES

An interesting thing about memristors is that they do not

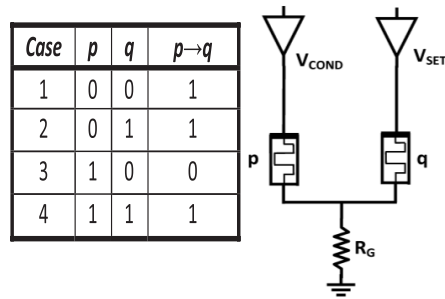


Figure 2: The imply function. The initial values of p and q are the input bits, with q being the output bit after applying the voltages V_{set} and V_{cond}

implement the same logic that conventional transistor based gates would. In order to perform logic in a memristor crossbar array architecture, material implication logic (IMP) is used. A truth table of the imply function along with an imply logic gate is given in Figure 2 [6]. Just like nand gates imply gates are capable of implementing any boolean function, allowing for crossbar arrays of memristors to perform any logic functions. In either of the gates the memristors are connected to a resistor R_G where the resistance of R_G is between R_{Off} and R_{On} . What exactly happens during the imply gate with memristors P and Q with initial states p and q is as follows:

- Apply voltage V_{cond} to P and V_{set} to Q where ($|V_{cond}| < |V_{set}|$)
- If $p = 1$ (low resistance), the voltage on the shared terminal is approximately V_{cond} and the voltage on Q is $V_{set} - V_{cond}$, which is small enough that the state of Q is unchanged.
- If $p = q = 0$ (high resistance), then the resistance on Q is approximately V_{set} , and Q is switched to 1.
- If $p = 0$ and $q = 1$, the state of Q is also unchanged.

5. COMPUTATION IN MEMORY

5.1 Von Neumann Bottleneck

Modern computing designs are based on Von Neumann architecture. In this architecture the CPU and main memory are two physically separate things that communicate through buses. A diagram of how this communication works is shown in Figure 3 [13]. The transfer of information through these buses results in the Von Neumann Bottleneck where the data transfer rate is significantly less than the data that needs to be transferred. To make things worse the bus can only access either the CPU or main memory, not both at the same time. This results in the data transfer rate being lower than speed at which the CPU can work by forcing it to wait for information. This problem has been getting worse as both main memory size and CPU speeds have increased much faster than the data transfer rates. The transfer of data is also highly energy intensive. It is estimated that communication of data takes up 70 to 90% of energy consumption, leaving only 10 to 30% of energy consumption for performing computations [5]. For example, executing a

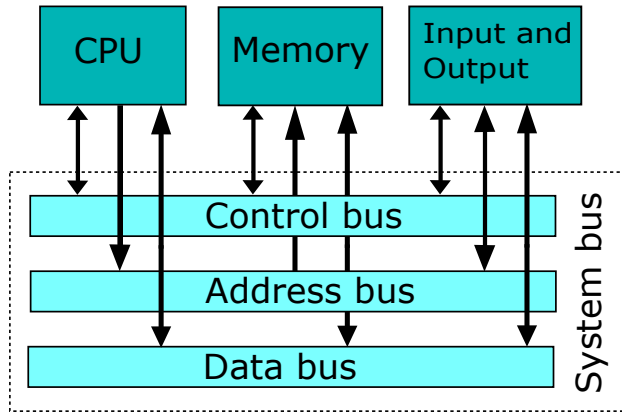


Figure 3: Communication in Von Neumann architecture

multiply instruction in 45nm technology uses about 70 pJ, where as the actual operation only uses 4 pJ.

There are several methods for mitigating the Von Neumann bottleneck but the problem persists. Some of these methods include using SRAM caches or providing an on-chip CPU stack. It is interesting to note that these methods are essentially attempts at bringing the memory closer to the CPU. SRAM caches have their own limitations though as they have poor density, expensive to manufacture, and are experiencing increasing energy leakage as they are increasingly scaled down.

5.2 Basic Design

A solution to the Von Neumann bottleneck is to have the CPU and main memory merged as proposed by Hamdioui et al [5]. In CIM, computation in memory, the computation and data storage are integrated in a crossbar array. Memristors in a crossbar array can be used for data storage and logic which allows computations and memory to be integrated into the same chip. This removes the need for data transfer through buses that have poor data transfer rates. This also removes the need to be constantly accessing things like SRAM caches which have high energy consumption, poor density (due to the fact that it takes between 4 to 10 transistors to represent a bit in SRAM), and information bottle-necking. Since the crossbar array has such high densities and the memristors themselves have little to no power leakage and good read/write switching time, there would be enough room for these to be combined without needing to increase the size of the processor to match the total storage and processing power of a conventional architecture. A more succinct overview of the advantages of CIM is as follows:

- Tightly integrated (scalable to 5nm) computation-in-memory crossbar architecture supporting massive parallelism.
- Little to no power leakage. Current VN architectures are beginning to run into scaling problems due to power leakages from constantly accessing SRAM caches.
- Significant performance improvement at lower energy and area.

| Metric | Archit. | DNA sequencing | 10 ⁶ additions |
|--------------------------|---------|----------------|---------------------------|
| Energy –Delay/operations | Conv. | 2.02e-03 | 1.5043e-18 |
| | CIM | 2.34e-06 | 9.2570e-21 |
| Computing Efficiency | Conv. | 4.11e01 | 6.5226e+9 |
| | CIM | 3.70e04 | 3.9063e+12 |
| Performance Area | Conv. | 5.73e06 | 5.1118e+09 |
| | CIM | 8.28e09 | 4.9164e+12 |

Table 2: Results of simulated data-sets. Unfortunately the source only used these as comparisons, and did not provide any actual units.

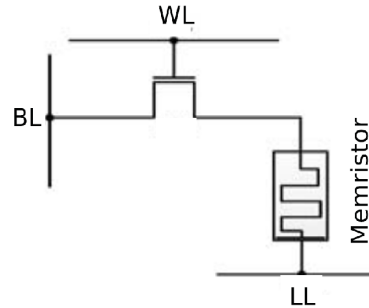


Figure 4: 1T1R cell: BL = Bitline, WL = Wordline

The memristor based crossbar construction also uses materials and designs that CMOS manufacturing techniques can be applicable to. Outside of the crossbar array, the control and communication can be made using standard CMOS based technology, but it would require a significant redesign to be compatible with a CIM architecture. Because of this, the research paper from Hamdioui et al. is proposing CIM as a concept and does not appear to have a fully designed architecture at hand. Computations of this architecture are simulated based on assumptions of how the architecture would behave.

5.3 Results on Large Data-sets

Table 2 displays the simulated results between conventional and CIM architecture from [5]. The DNA sequencing results were computed by performing a common solution for comparing two DNA sequences in which a sorted index of reference DNA is created in order to identify the locations of matches or mismatches in another sequence. In the particular case set up by Hamdioui et al. they are comparing 200 GB of DNA data to 3GB of healthy reference. The other example is for 10⁶ parallel addition operations. The first row of the table represents the the energy-delay product per operations, the second row the computation efficiency defined as the number of operations per required energy, and the third row is the number of operations per area. These simulations were based off of a fairly large table of assumptions provided by Hamdioui et al. [5].

6. 1T1R

One of the main problems with the crossbar array is the sneak path problem. Since electricity always looks for a path with the least resistance, there is little preventing the previ-

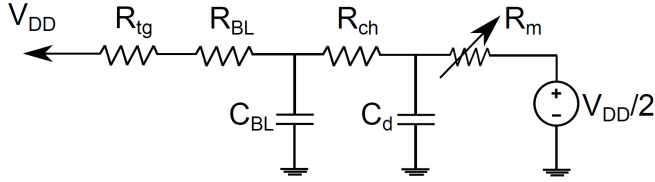


Figure 5: Circuit of a 1T1R cell during a write. V_{BL} is set to V_{DD} for writing 1, and 0 for writing 0.

ously described crossbar array from having what is called a sneak path. This results in an alternative path being created when reading/writing where instead of going through the desired memristor, the current may instead travel through different memristors. This is far from an unsolved problem as there are multiple ways of dealing with this, but one method in particular is the 1T1R cell as proposed by Zangeneh et al. [14]. It stands for one transistor, one resistor (in this case the resistor is a memristor) and has some parallels with DRAM cells, as they are made up of one transistor, one capacitor. A 1T1R equivalent cell during a write operation is shown in figure 4.

Out of the methods for dealing with the sneak-path problem this one appears to be the simplest and has the highest access times. The memristor used in this approach is the standard TiO_2 based one. Like DRAM, the proposed 1T1R architecture has a wordline to select a row of cells and a bitline to select columns. During a write a voltage V_{DD} is applied to the wordline, and a positive or negative voltage is applied across the memristor for writing 1 or 0 logic. This is done by either charging the bitline to V_{DD} (for logic 1) or discharging it to 0 V (for logic 0), and applying a voltage $\frac{V_{DD}}{2}$ at node LL.

6.1 Read/Write Properties of 1T1R

This subsection will provide the four main equations for the read and write models, regarding the time to read/write and the energy to read/write. Comparing the results of the models to the results to Table 1, they seem to agree with each other. Figure 5 provides a circuit diagram during a write procedure.

6.1.1 Write Time Model

The equation to model the time necessary to write to a memristor is:

$$T_w = \frac{L^2(1 + \beta)}{2\mu_v V_A}$$

In this equation the T in T_w stands for time and the subscript w stands for write. L is the thickness of the memristor, β is the ratio of R_{OFF} and R_{ON} , V_A is the magnitude of the applied voltage, and μ_v is a constant for the mobility of the oxygen vacancy. According to this equation then, if the thickness of the memristor or the difference in resistance between an off state and on state increase, then the time to write will increase. If the applied voltage is increased the time to write will decrease. Using this model a read time of approx. 7ns was found with $\beta = 10$ and $L = 1nm$ when writing a 1, but when writing a 0 with the same parameters it can be as low as 4 ns. A graph of the model is provided in Figure 6 [14].

6.1.2 Read Time Model

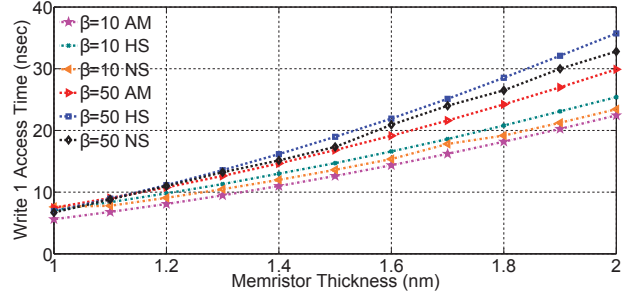


Figure 6: Analytical model vs HSPICE simulations for write 1 access time as a function of memristor thickness for different β (On/Off ratio). AM = Analytical model ignoring bitline capacitance, HS = Hspice simulations and NS = Numerical solution accounting for bitline capacitance.

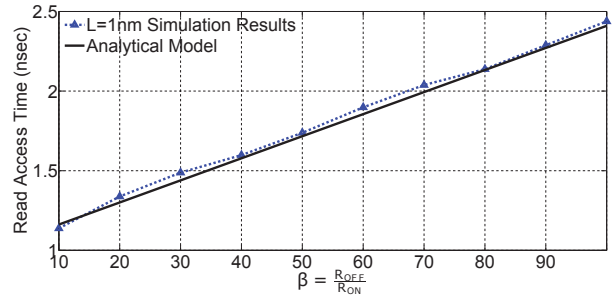


Figure 7: Read time model: Analytical model versus HSPICE simulation results for read access time of the 1T1R cell as a function of β for different memristor thicknesses L .

The equation to model the time required to read is:

$$T_R = 0.69(R_{ch} + R_{BL} + R_{OFF})C_{BL}$$

R_{ch} is the resistance of the access transistor, R_{BL} is the resistance of the bitline resistor, and C_{BL} is the bitline capacitance. Figure 7 provides an illustration with $R_{ON} = 100 \Omega$, $R_{tg} = 582 \Omega$, and $C_{BL} = 200 \text{ fF}$ [14].

6.1.3 Write Energy Model

The model for energy consumption during a write procedure is:

$$E_w = \frac{V_{DD} I_1}{2(\zeta)}$$

I_1 is $\int_{.1}^{.9} \frac{1}{1-x^4} dx$, the integral of the inverse of the window function which models the nonlinear rate of state change of a memristor and $\zeta = \frac{\mu_v R_{ON}}{L^2}$. Figure 8 graphs the model as a function of memristor thickness with ($R_{tg} = 582 \Omega$, $R_{ON} = 100 \Omega$, and $C_{BL} = 200 \text{ fF}$) [14].

6.1.4 Read Energy Model

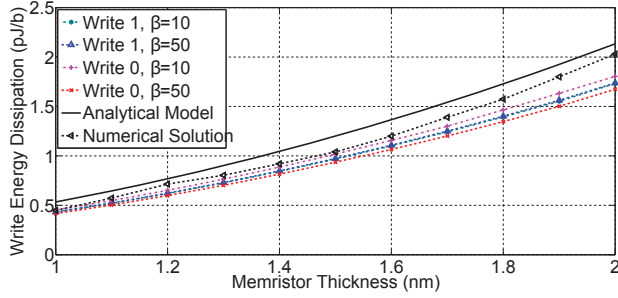


Figure 8: Write Energy Model: Analytical model ignoring the bitline capacitance and Numerical solution considering bitline capacitance.

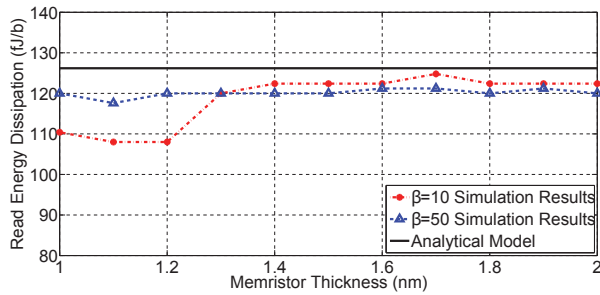


Figure 9: Comparison between the proposed model and HSPICE simulations of read energy.

The model for energy consumption during a read procedure is:

$$E_R = 0.63C_{BL}V_{DD}^2$$

Figure 9 provides a graph of the model, with $R_{On} = 100\Omega$, $C_{BL} = 200fF$, which shows that the energy to read is independent of memristor thickness [14].

7. OTHER APPLICATIONS

Aside from memory and logical computations, memristors have many other potential uses. One usage in particular that comes up often is its use in neural networks. There is much research applying memristors to simulate synapses in cognitive computing since memristance is somewhat analogous to how synapses behave. The more a synapse is used the stronger its connection becomes, similar to how a memristor can become more conductive as a current is applied to it. This makes memristors a prime candidate for storing information not to be interpreted as a binary number but as a range of values that could represent a synapse [7].

8. CONCLUSIONS

As covered in the paper, the memristor appears to be a promising new device for high density, high speed, and energy efficient computing. The history of memristors is somewhat complicated. It has been shown to be suitable for new computing architectures that do not suffer from a communi-

cations bottleneck. It also has the potential to replace many of the mediums for data storage such as flash and DRAM as it appears to be a prime candidate as a universal memory. There is still likely much to do before memristors start replacing transistors in processors, but the potential is there.

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